



# 700V Super-junction Power MOSFET

## Description

### 700V Super-junction Power MOSFET

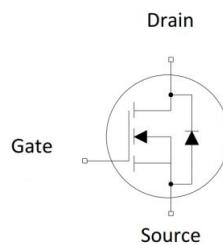
Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle. The Multi-EPI SJ MOSFET provide an extremely low switching, communication and conduction losses device with highest robustness make especially resonant switching applications more reliable, more efficient, lighter and cooler, designed by Wuxi Unigroup Microelectronics Company.

## Features

- Very low FOM  $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- Easy to use/drive
- RoHS compliant

## Applications

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- Charger



## Device Marking and Package Information

Device	Package	Marking
TPB70R950M	TO-263	
TPD70R950M	TO-252	70R950M

## Key Performance Parameters

Parameter	Value	Unit
$V_{DS} @ T_{j,max}$	750	V
$R_{DS(on),max}$	0.95	$\Omega$
$Q_{g,typ}$	9.6	nC
$I_D$	4.5	A
$I_{D,pulse}$	13.5	A
$E_{OSS} @ 400V$	1.05	$\mu J$
Body Diode $dI_F/dt$	500	A/ $\mu s$

**Absolute Maximum Ratings  $T_C = 25^\circ\text{C}$ , unless otherwise noted**

Parameter	Symbol	Value	Unit
Continuous Drain Current $T_C = 25^\circ\text{C}$	$I_D$	4.5	A
$T_C = 100^\circ\text{C}$		2.7	
Pulsed Drain Current (note1)	$I_{D,\text{pulse}}$	13.5	A
Gate-Source Voltage	$V_{GSS}$	$\pm 30$	V
Single Pulse Avalanche Energy (note2)	$E_{AS}$	50	mJ
Repetitive Avalanche Energy (note2)	$E_{AR}$	0.15	mJ
Avalanche Current	$I_{AR}$	1.0	A
MOSFET dv/dt Ruggedness, $V_{DS} = 0 \dots 480\text{V}$	dv/dt	50	V/ns
Power Dissipation For TO-263,TO-252	$P_D$	37	W
Continuous Diode Forward Current	$I_S$	3.8	A
Diode Pulsed Current (note1)	$I_{S,\text{pulse}}$	13.5	
Reverse Diode dv/dt (note3)	dv/dt	15	V/ns
Maximum Diode Commutation Speed (note3)	di/dt	500	A/ $\mu\text{s}$
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	-55~+150	°C

**Thermal Resistance For TO-263,TO-252**

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{thJC}$	3.4	°C/W
Thermal Resistance, Junction-to-Ambient	$R_{thJA}$	62	

**Electrical Characteristics**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

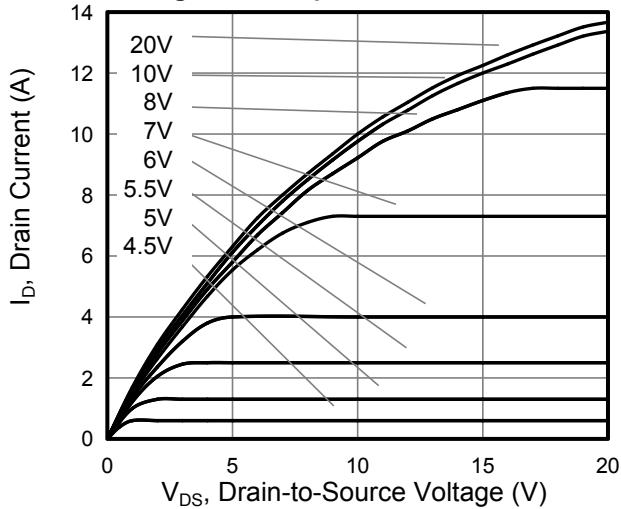
Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	700	--	--	V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 700\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 25^\circ\text{C}$	--	--	1	$\mu\text{A}$
		$V_{\text{DS}} = 700\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 150^\circ\text{C}$	--	--	100	
Gate-Source Leakage Current	$I_{\text{GSS}}$	$V_{\text{GS}} = \pm 20\text{V}$	--	--	$\pm 1$	$\mu\text{A}$
Gate-Source Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	2.5	--	4.0	V
Drain-Source On-State-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 2\text{A}$	--	0.87	0.95	$\Omega$
Gate Resistance	$R_G$	$f = 1.0\text{MHz}$ open drain	--	5	--	$\Omega$
<b>Dynamic Characteristics</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 100\text{V}, f = 1.0\text{MHz}$	--	320	--	$\text{pF}$
Output Capacitance	$C_{\text{oss}}$		--	18	--	
Reverse Transfer Capacitance	$C_{\text{rss}}$		--	2.1	--	
Total Gate Charge	$Q_g$	$V_{\text{DD}} = 520\text{V}, I_D = 4.5\text{A}, V_{\text{GS}} = 10\text{V}$	--	9.6	--	$\text{nC}$
Gate-Source Charge	$Q_{\text{gs}}$		--	1.9	--	
Gate-Drain Charge	$Q_{\text{gd}}$		--	4.3	--	
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 400\text{V}, I_D = 4.5\text{A}, R_G = 25\Omega$	--	54	--	$\text{ns}$
Turn-on Rise Time	$t_r$		--	62	--	
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		--	86	--	
Turn-off Fall Time	$t_f$		--	51	--	
<b>Drain-Source Body Diode Characteristics</b>						
Body Diode Forward Voltage	$V_{\text{SD}}$	$T_J = 25^\circ\text{C}, I_{\text{SD}} = 2\text{A}, V_{\text{GS}} = 0\text{V}$	--	0.9	1.2	V
Reverse Recovery Time	$t_{\text{rr}}$	$V_R = 400\text{V}, I_F = 4.5\text{A}, di_F/dt = 100\text{A}/\mu\text{s}$	--	271	--	$\text{ns}$
Reverse Recovery Charge	$Q_{\text{rr}}$		--	3.1	--	$\mu\text{C}$
Peak Reverse Recovery Current	$I_{\text{rrm}}$		--	23	--	A

**Notes**

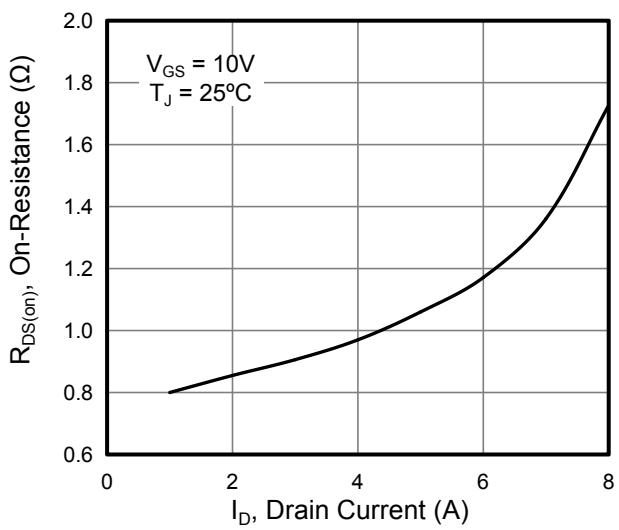
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $I_{\text{AS}} = 1.0\text{A}, V_{\text{DD}} = 50\text{V}, R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3. Identical low side and high side switch with identical  $R_G$

**Typical Characteristics**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

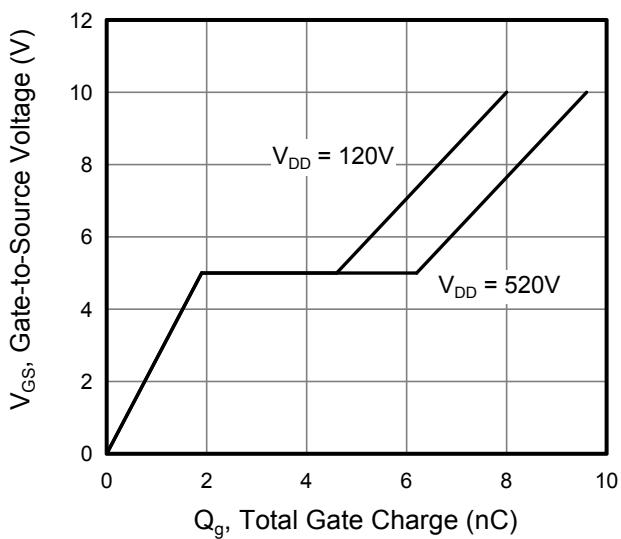
**Figure 1. Output Characteristics**



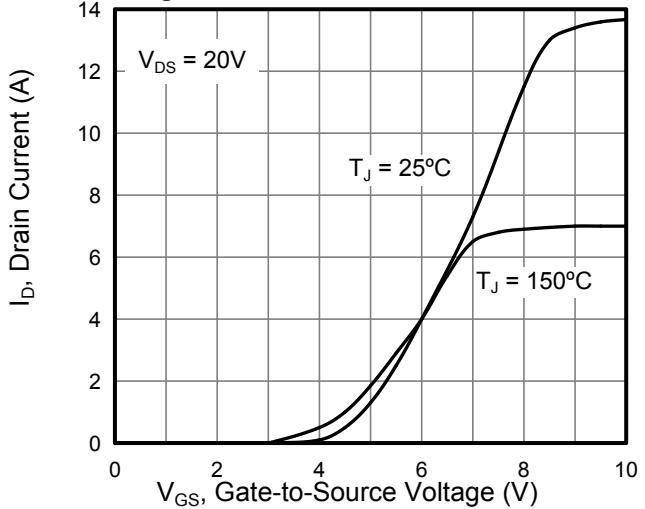
**Figure 3. On-Resistance vs. Drain Current**



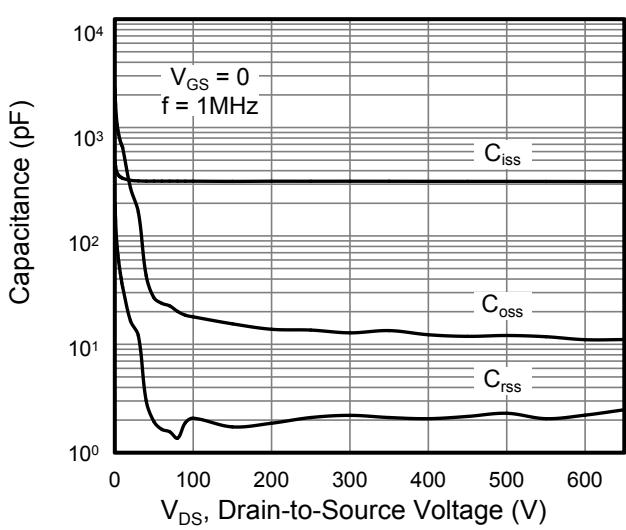
**Figure 5. Gate Charge**



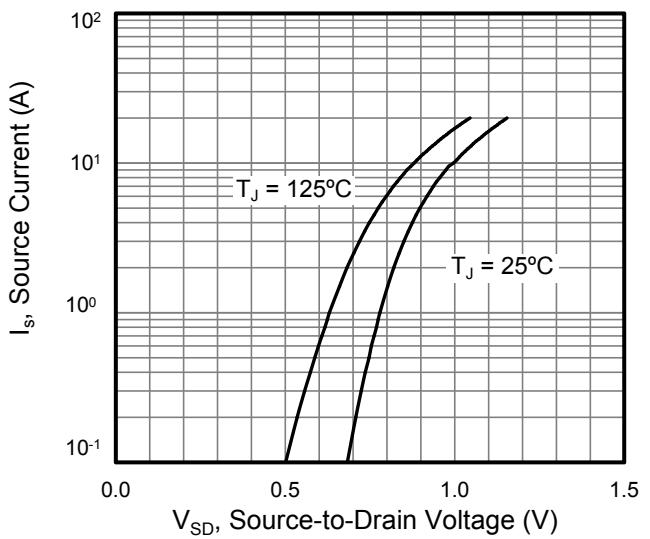
**Figure 2. Transfer Characteristics**



**Figure 4. Capacitance**

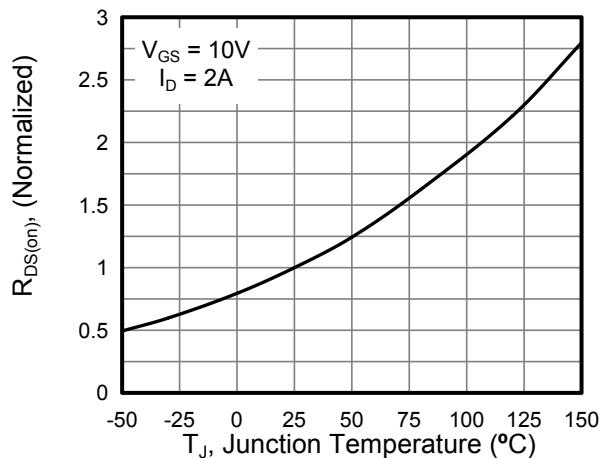


**Figure 6. Body Diode Forward Voltage**

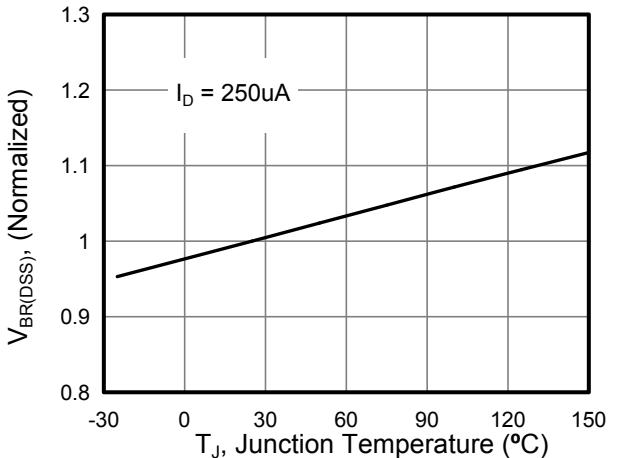


**Typical Characteristics**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

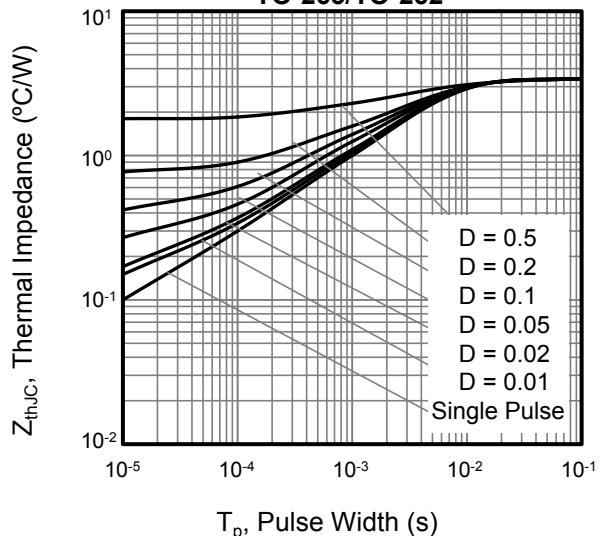
**Figure 7. On-Resistance vs. Junction Temperature**



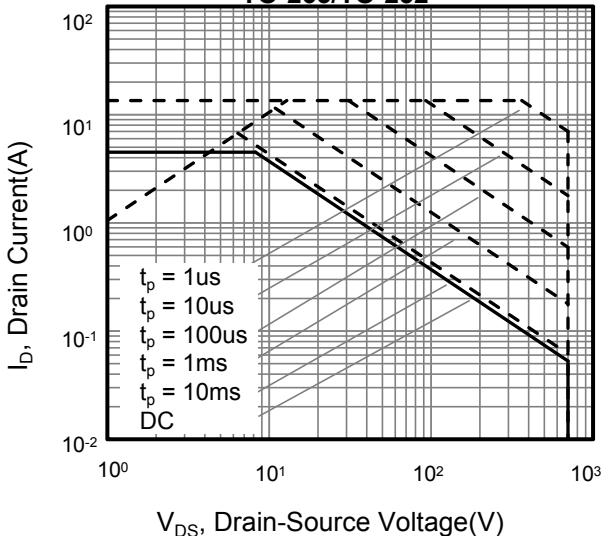
**Figure 8. Breakdown voltage vs. Junction Temperature**



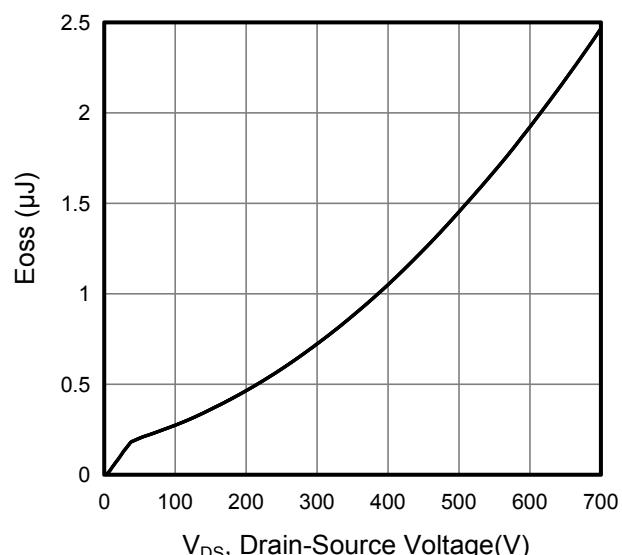
**Figure 9. Transient Thermal Impedance For TO-263/TO-252**

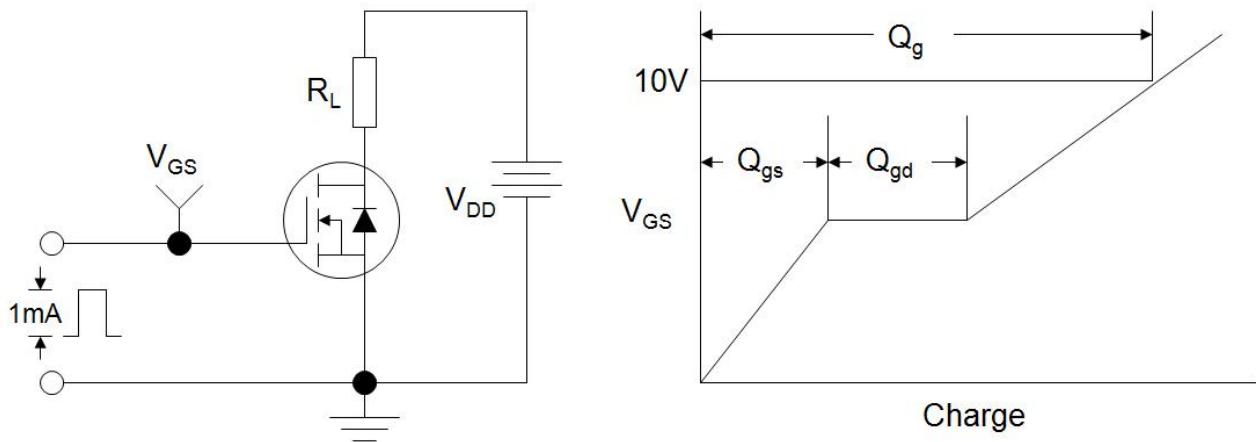
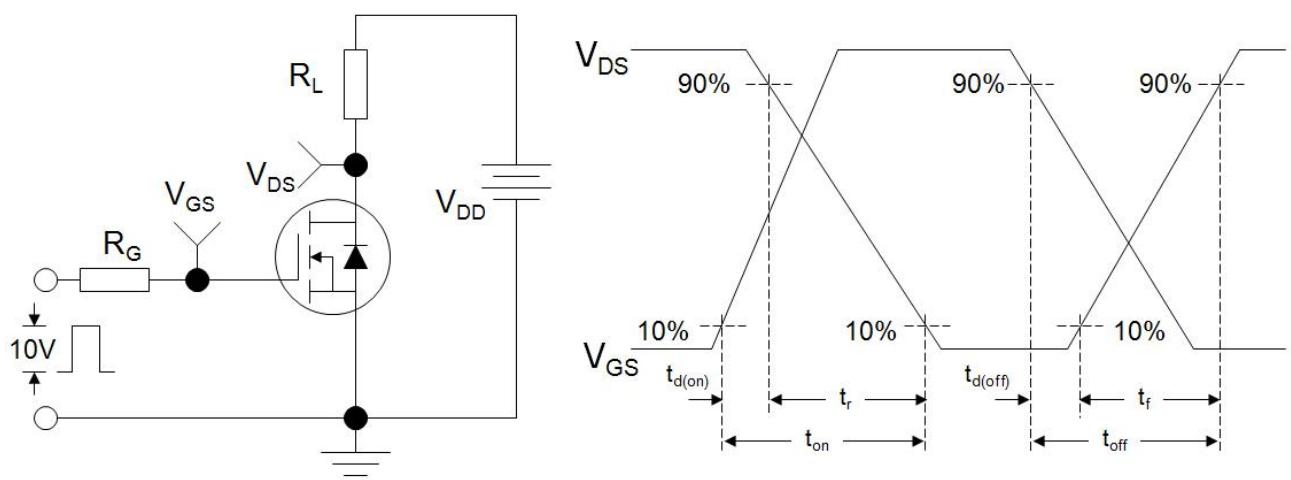
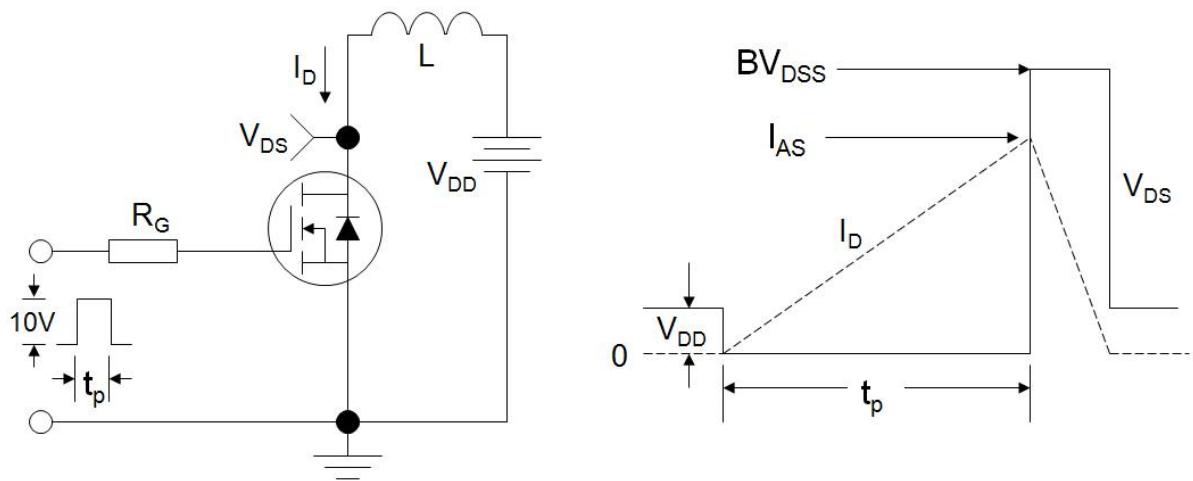


**Figure 10. Safe Operation Area For TO-263/TO-252**



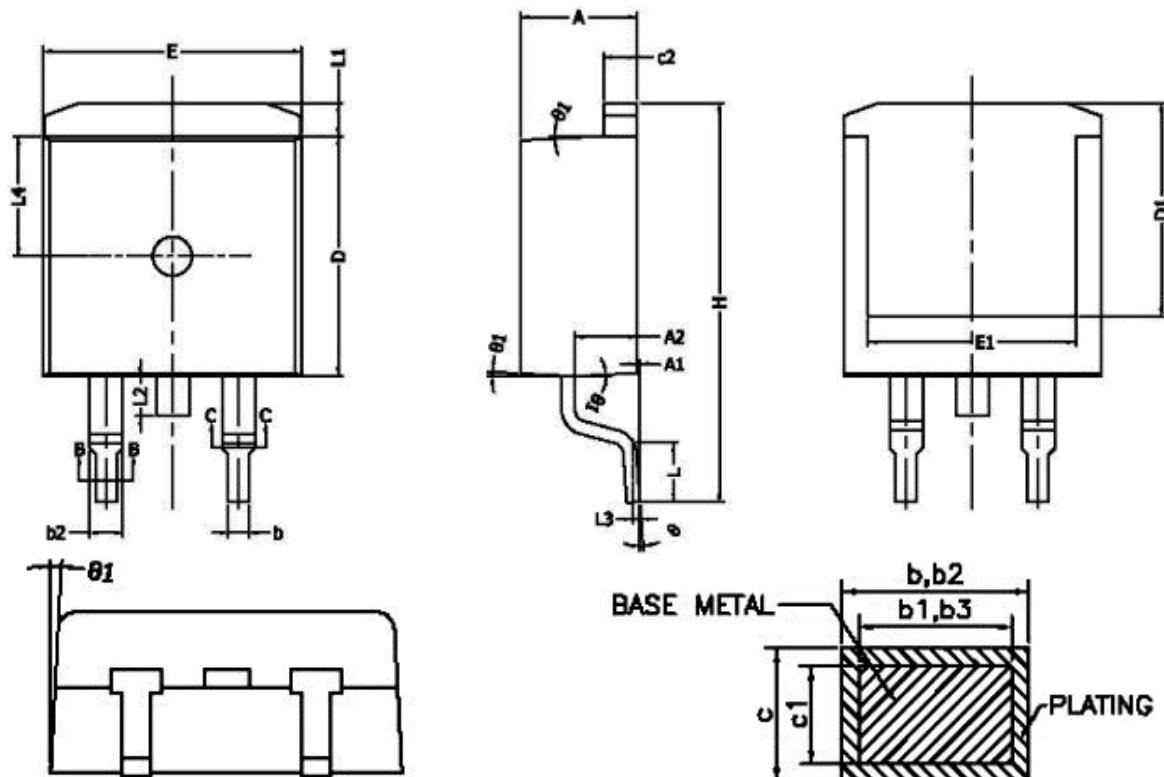
**Figure 11. Typ. Coss Stored Energy**



**Figure A: Gate Charge Test Circuit and Waveform**

**Figure B: Resistive Switching Test Circuit and Waveform**

**Figure C: Unclamped Inductive Switching Test Circuit and Waveform**




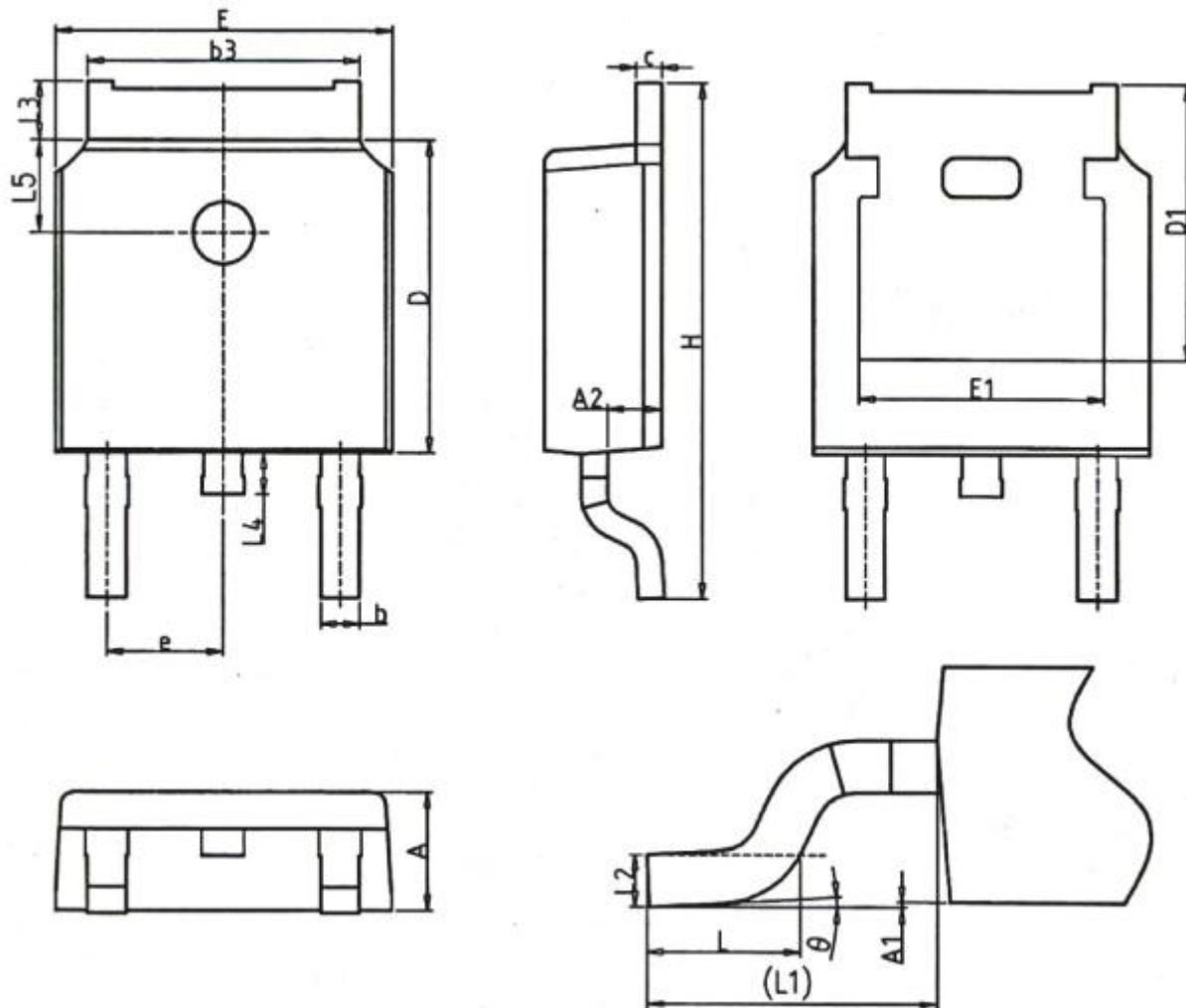
## TO-263 (封装厂 I)



SECTION B-B&amp;C-C

SYMBOL	MIN	NOM	MAX
A	4.40	4.50	4.60
A1	0	0.10	0.25
A2	2.20	2.40	2.60
b	0.76	--	0.89
b1	0.75	0.80	0.85
b2	1.23	--	1.37
b3	1.22	1.27	1.32
c	0.47	--	0.60
c1	0.46	0.51	0.56
c2	1.25	1.30	1.35
D	9.10	9.20	9.30
D1	8.00	--	--
E	9.80	9.90	10.00
E1	7.80	--	--
e	2.54 BSC		
H	14.90	15.30	15.70
L	2.00	2.30	2.60
L1	1.17	1.27	1.40
L2	--	--	1.75
L3	0.25BSC		
L4	4.60 REF		
θ	0°	--	8°
θ1	1°	3°	5°

## TO-252 (封装厂 H)



Unit:mm			
Symbol	Min.	Nom	Max.
A	2.20	2.30	2.38
A1	0.00	-	0.20
A2	0.97	1.07	1.17
b	0.68	0.78	0.90
b3	5.20	5.33	546
c	0.43	0.53	0.61
D	5.98	6.10	6.22
D1	5.30 REF		
E	6.40	6.60	6.73
E1	4.63	-	-

Unit:mm			
Symbol	Min.	Nom	Max.
e	2.286 BSC		
H	9.40	10.10	10.50
L	1.38	1.50	1.75
L1	2.90 REF		
L2	0.51 BSC		
L3	0.88	-	1.28
L4	0.50	-	1.00
L5	1.65	1.80	1.95
θ	0°	-	8°



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